

# FQB22P10TM-F085

## 100V P-Channel MOSFET

### **General Description**

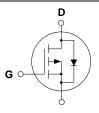
These P-Channel enhancement mode power field effect transistors are produced using ON Semiconductor proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as audio amplifier. high efficiency switching DC/DC converters, and DC motor control.

### **Features**

- -22A, -100V,  $R_{DS(on)}$  = 0.125 $\Omega$  @V<sub>GS</sub> = -10 V Low gate charge ( typical 40 nC)
- Low Crss (typical 160 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- 175°C maximum junction temperature rating
- · Qualified to AEC Q101
- · RoHS Compliant





## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol **Parameter** FQB22P10TM\_F085 Units  $V_{DSS}$ Drain-Source Voltage -100 - Continuous (T<sub>C</sub> = 25°C) -22  $I_D$ **Drain Current** Α - Continuous (T<sub>C</sub> = 100°C) -15.6 Α  $I_{DM}$ **Drain Current** - Pulsed -88 Α (Note 1) Gate-Source Voltage ±30  $V_{GSS}$ E<sub>AS</sub> Single Pulsed Avalanche Energy 710 (Note 2) mJ  $I_{AR}$ Avalanche Current -22 Α (Note 1)  $\mathsf{E}_{\mathsf{AR}}$ Repetitive Avalanche Energy 12.5 mJ (Note 1) dv/dt Peak Diode Recovery dv/dt -6.0 V/ns (Note 3) Power Dissipation  $(T_A = 25^{\circ}C)$ 3.75 W  $P_D$ Power Dissipation  $(T_C = 25^{\circ}C)$ 125 W - Derate above 25°C 0.83 W/°C  $T_J$ ,  $T_{STG}$ Operating and Storage Temperature Range -55 to +175 °C Maximum lead temperature for soldering purposes, °C  $T_{l}$ 300 1/8" from case for 5 seconds

## Thermal Characteristics

Symbol	Parameter	Тур	Max	Units	
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.2	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W	
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-100			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		-0.1		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -100 V, V <sub>GS</sub> = 0 V			-1	μΑ
		V <sub>DS</sub> = -80 V, T <sub>C</sub> = 125°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-2.0		-4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -11 A		0.096	0.125	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -40 \text{ V}, I_{D} = -11 \text{ A}$ (Note 4)		13.5		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		460 160	1500 600 200	pF pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			160	200	pF
Switchi	ing Characteristics					
$t_{d(on)}$	Turn-On Delay Time	$V_{DD}$ = -50 V, $I_{D}$ = -22 A, $R_{G}$ = 25 $\Omega$ (Note 4, 5)		17	45	ns
t <sub>r</sub>	Turn-On Rise Time			170	350	ns
$t_{d(off)}$	Turn-Off Delay Time			60	130	ns
t <sub>f</sub>	Turn-Off Fall Time			110	230	ns
$Q_g$	Total Gate Charge	V <sub>DS</sub> = -80 V, I <sub>D</sub> = -22 A, V <sub>GS</sub> = -10 V		40	50	nC
Q <sub>gs</sub>	Gate-Source Charge			7.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		21		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-22	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				-88	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -22 \text{ A}$			-4.0	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -22 A,		110		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.6		μС

### Notes:

- **Notes:** 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.2mH,  $I_{AS}$  = -22A,  $V_{DD}$  = -25V,  $R_{G}$  = 25  $\Omega$ , Starting  $T_{J}$  = 25°C 3.  $I_{SD}$  ≤ -22A,  $I_{J}$  = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s,  $I_{J}$  = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

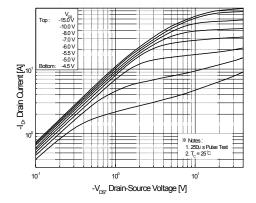


Figure 1. On-Region Characteristics

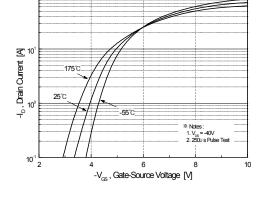


Figure 2. Transfer Characteristics

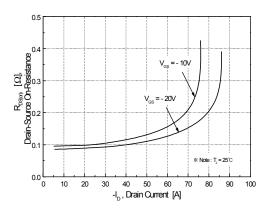


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

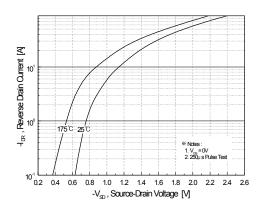


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

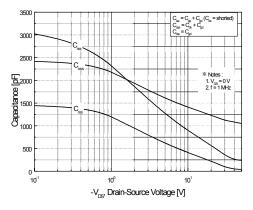


Figure 5. Capacitance Characteristics

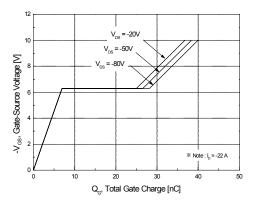


Figure 6. Gate Charge Characteristics

# -BV<sub>rss</sub>, (Nomelized) Dain-Source Breakdown Voltage 0.8 L -100

Typical Characteristics (Continued)

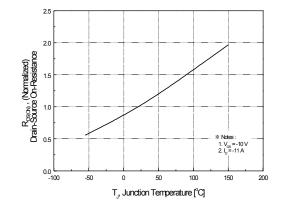
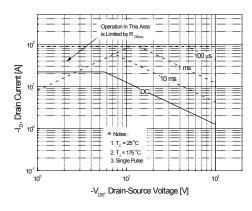


Figure 7. Breakdown Voltage Variation vs. Temperature

T<sub>.</sub>, Junction Temperature [°C]

150

Figure 8. On-Resistance Variation vs. Temperature



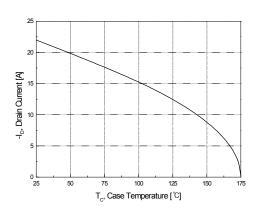


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

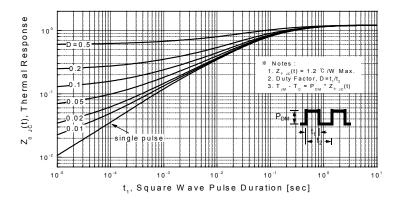
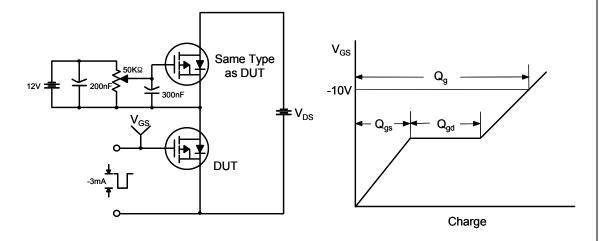
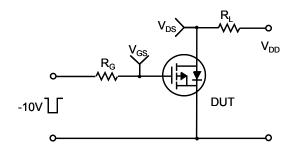


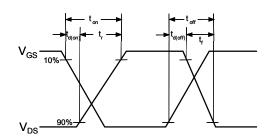
Figure 11. Transient Thermal Response Curve

### **Gate Charge Test Circuit & Waveform**

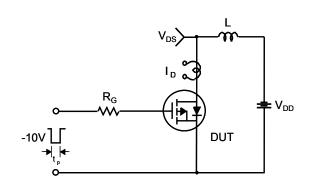


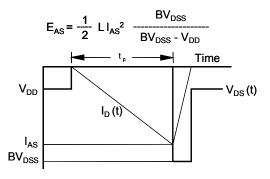
### **Resistive Switching Test Circuit & Waveforms**



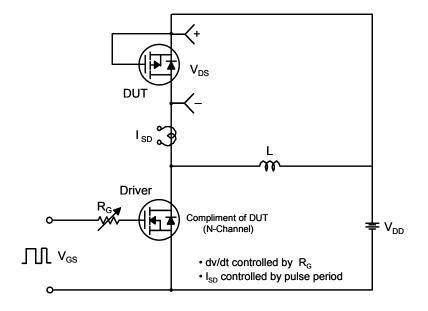


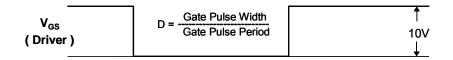
### **Unclamped Inductive Switching Test Circuit & Waveforms**

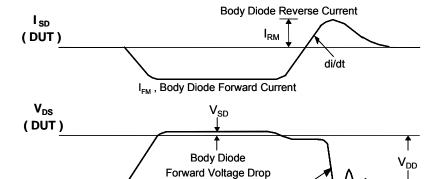




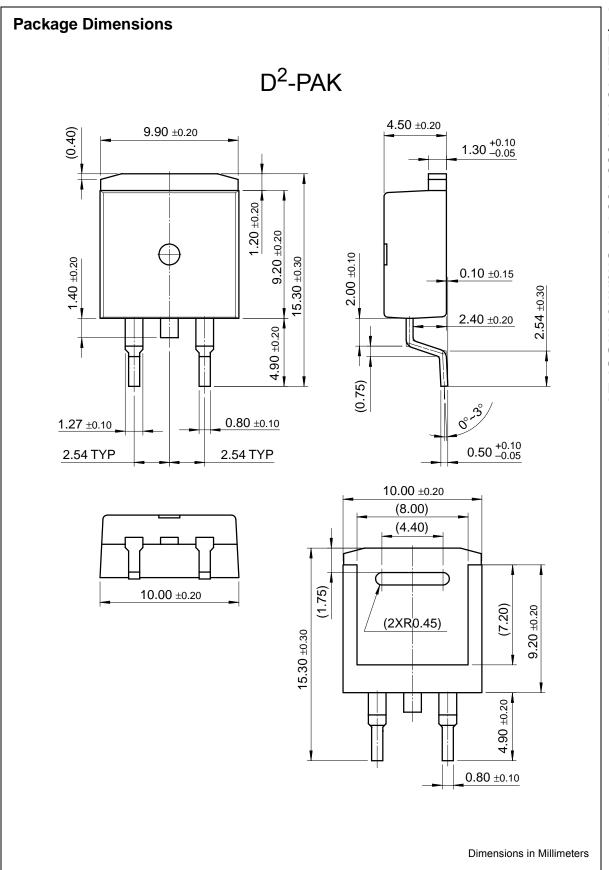
### Peak Diode Recovery dv/dt Test Circuit & Waveforms







Body Diode Recovery dv/dt



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